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<u>L19</u> 18 and 117	2	<u>L19</u>
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<u>L17</u> (713/401-601)[CCLS]	3050	<u>L17</u>
<u>L16</u> (714/15)[CCLS]	566	<u>L16</u>
<u>L15</u> (714/15)![CCLS]	2	<u>L15</u>
<u>L14</u> 19 and 14	2851	<u>L14</u>
<u>L13</u> 110 and 14	132	<u>L13</u>
<u>L12</u> (110 and 14)[CCLS]	0	<u>L12</u>
<u>L11</u> (110 and 14)![CCLS]	0	<u>L11</u>
<u>L10</u> (710/261-266)![CCLS]	805	<u>L10</u>
<u>L9</u> (712/2-300)[CCLS]	10878	<u>L9</u>
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<u>L8</u>	L7 and l2	103	<u>L8</u>
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<u>L6</u>	L5 and l4	2083	<u>L6</u>
<u>L5</u>	L2 and l3	5997	<u>L5</u>
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<u>L3</u>	select\$4 near5 address\$3	111486	<u>L3</u>
<u>L2</u>	(activat\$4 or inactivat\$4 or inhibit\$4 or disabl\$4 or enabl\$4 or hold\$4 or held or halt\$3) near6 interrupt\$3	50508	<u>L2</u>
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